



FQD30N06L / FQU30N06L

60V LOGIC N-Channel MOSFET

General Description

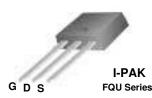
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

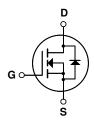
This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- 24A, 60V, $R_{DS(on)} = 0.039\Omega$ @ $V_{GS} = 10V$
- Low gate charge (typical 15 nC)
- · Low Crss (typical 50 pF)
- Fast switching
- · 100% avalanche tested
- · Improved dv/dt capability
- 150°C maximum junction temperature rating
- Low level gate drive requirements allowing direct operation form logic drivers
- · RoHS Compliant







Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQD30N06L / FQR30N06L	Units
V _{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°C)		24	Α
	- Continuous (T _C = 100°C)		15	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	96	Α
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	400	mJ
I _{AR}	Avalanche Current	(Note 1)	24	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	4.4	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P _D	Power Dissipation (T _A = 25°C) *		2.5	W
	Power Dissipation (T _C = 25°C)		44	W
	- Derate above 25°C		0.35	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.85	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		50	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		110	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter Test Conditions		Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$				V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced t	to 25°C	0.07		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$			1	μΑ
		V _{DS} = 48 V, T _C = 125°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = 5 V, I _D = 250 μA	1.0		2.5	V
R _{DS(on)}	Static Drain-Source	V _{GS} = 10 V, I _D = 12 A		0.031	0.039	
D3(0H)	On-Resistance			0.038	0.047	Ω
9FS	Forward Transconductance	d Transconductance $V_{DS} = 25 \text{ V}, I_D = 12 \text{ A}$ (Note 4)		23		S
Dynam	ic Characteristics Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		800	1040	pF
Coss	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		270	350	pF
C _{rss}	Reverse Transfer Capacitance			50	65	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V 00 V I 40 A		15	40	ns
t _r	Turn-On Rise Time	$V_{DD} = 30 \text{ V}, I_{D} = 16 \text{ A},$		210	430	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 25 \Omega$		55	120	ns
t _f	Turn-Off Fall Time	4)	lote 4, 5)	110	230	ns
Q _g	Total Gate Charge	$V_{DS} = 48 \text{ V}, I_{D} = 32 \text{ A},$ $V_{GS} = 5 \text{ V}$ (Note 4, 5)		15	20	nC
Q _{gs}	Gate-Source Charge			3.5		nC
Q _{gd}	Gate-Drain Charge			8.5		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
l _S	-Source Diode Characteristics and Maximum Ratings Maximum Continuous Drain-Source Diode Forward Current				24	Α
I _{SM}	Maximum Pulsed Drain-Source Diode F	rain-Source Diode Forward Current			96	Α
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 24 A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _F = 32 A,		55		ns
	1	4	L	-1		

- $\label{eq:Notes:Notes:1} \begin{tabular}{ll} \textbf{Notes:} \\ \textbf{1.} & \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature} \\ \textbf{2.} & \textbf{L} = \textbf{0.8mH, } |_{AS} = 24\text{A, } V_{DD} = 25\text{V, } R_{G} = 25~\Omega, \ \textbf{Starting} \ T_{J} = 25^{\circ} \textbf{C} \\ \textbf{3.} & \textbf{I}_{SD} \leq 32\text{A, } \text{di/dt} \leq 300\text{A/us, } V_{DD} \leq \text{BV}_{DSS,} \ \textbf{Starting} \ T_{J} = 25^{\circ} \textbf{C} \\ \textbf{4.} & \textbf{Pulse Test: Pulse width} \leq 300\text{us, Duty cycle} \leq 2\% \\ \textbf{5.} & \textbf{Essentially independent of operating temperature} \\ \end{tabular}$

Typical Characteristics

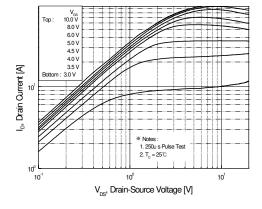


Figure 1. On-Region Characteristics

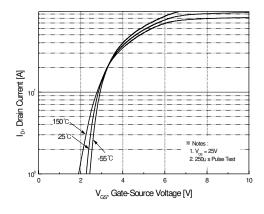


Figure 2. Transfer Characteristics

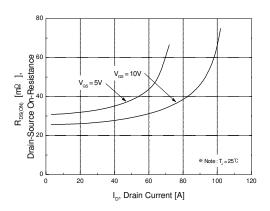


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

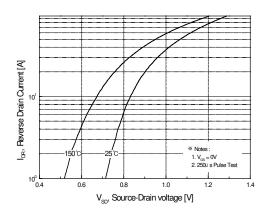


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

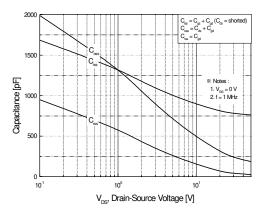


Figure 5. Capacitance Characteristics

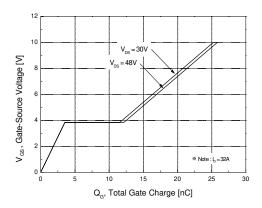
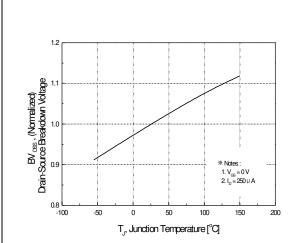


Figure 6. Gate Charge Characteristics



Typical Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

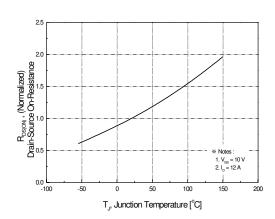


Figure 8. On-Resistance Variation vs. Temperature

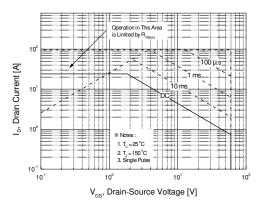


Figure 9. Maximum Safe Operating Area

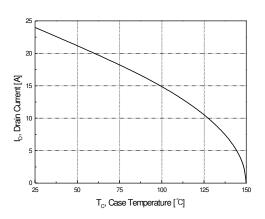


Figure 10. Maximum Drain Current vs. Case Temperature

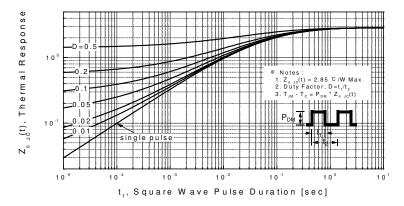
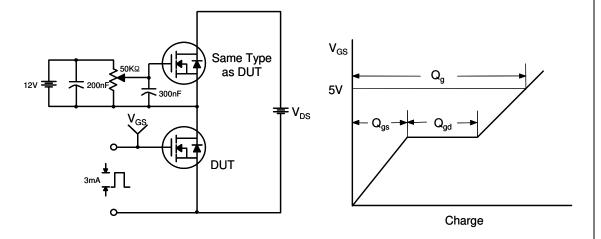
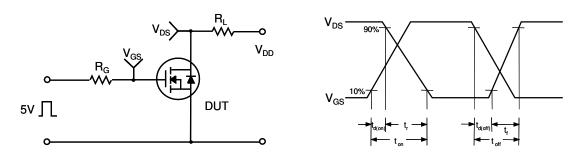


Figure 11. Transient Thermal Response Curve

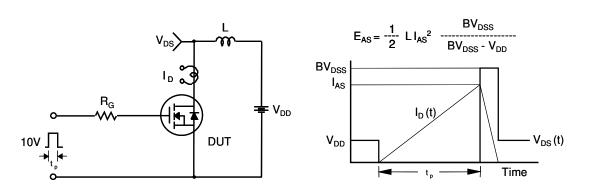
Gate Charge Test Circuit & Waveform



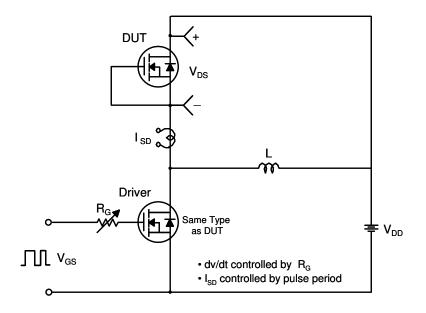
Resistive Switching Test Circuit & Waveforms

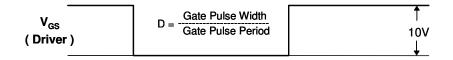


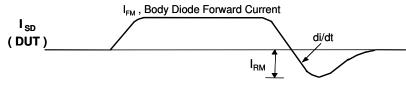
Unclamped Inductive Switching Test Circuit & Waveforms



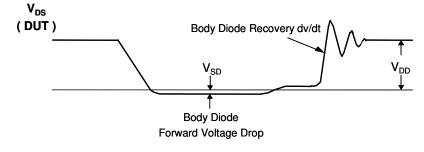
Peak Diode Recovery dv/dt Test Circuit & Waveform







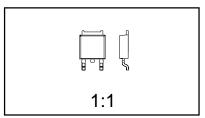
Body Diode Reverse Current



Mechanical Dimensions

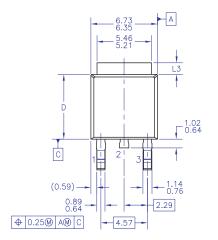
TO-252 (DPAK) (FS PKG Code 36)

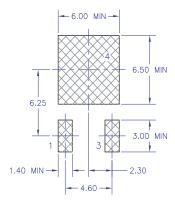




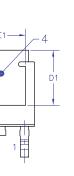
Scale 1:1 on letter size paper Dimensions shown below are in: millimeters

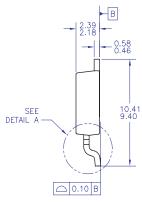
Part Weight per unit (gram): 0.33

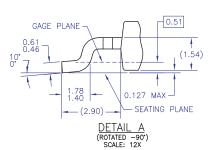




LAND PATTERN RECOMMENDATION







NOTES: UNLESS OTHERWISE SPECIFIED

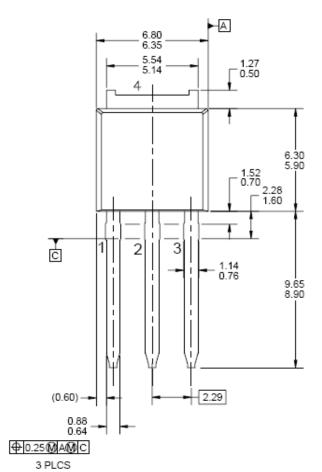
- UNLESS OTHERWISE SPECIFIED
 ALL DIMENSIONS ARE IN MILLIMETERS.
 THIS PACKAGE CONFORMS TO JEDEC, TO-252,
 ISSUE C, VARIATION AA & AB, DATED NOV. 1999.
 DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M-1994.
 HEAT SINK TOP EDGE COULD BE IN CHAMFERED
 CORNERS OR EDGE PROTRUSION.
 DIMENSIONS L3,D,E1&D1 TABLE:

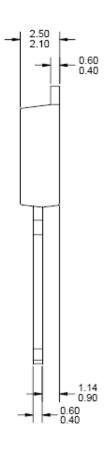
 [OPTION AA JOPTION AB]

	OPTION AA	OPTION AB
L3	0.89-1.27	1.52-2.03
D	5.97-6.22	5.33-5.59
E1	4.32 MIN	3.81 MIN
D1	5.21 MIN	4.57 MIN

Mechanical Dimensions

I - PAK





ф. п. п. п.

Dimensions in Millimeters





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